

Semiconductor saturable absorber model with circuitry

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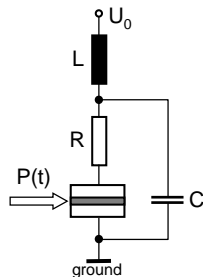
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I. PROBLEM DESCRIPTION

A short semiconductor section negatively biased with $U_0 < 0$ is often used as a saturable absorber. A pulse train $P(t)$ is injected causing an ac photocurrent. In order to model the behavior of the absorber under these conditions, its series resistivity R , wire inductivity L , and parasitic capacity C have to be considered.

II. MODEL COMPONENTS

I use the following circuit schema of semiconductor lasers, as given in the Petermann-Book.



The basic voltage-current relations of a resistivity, inductivity, and capacity are

$$U_R = RI_R, \quad U_L = LI_L, \quad \text{and} \quad C\dot{U}_C = I_C, \quad (1)$$

respectively. The intrinsic voltage-current relation of the semiconductor absorber can be modeled by the Fermi voltage

$$U_F(N) = U_g + U_T \ln \left(\frac{N}{n_t} \right), \quad eU_g = E_g, \quad eU_T = kT, \quad (2)$$

with temperature T , Boltzmann constant k , band gap E_g of the active layer, transparency concentration n_t . This simple logarithmic Boltzmann law is valid as long as N does not exceed n_t , which holds in the absorber regime of operation (but no more when operating the device as a laser). Furthermore, it has been used the reasonable assumption that $U_F = U_g$ holds at transparency.

The Fermi voltage depends on the excess carrier density, which in turn obeys the rate equation

$$\dot{N} = \frac{I}{eV} - r(N) - G(N)S(t). \quad (3)$$

I : injection current (positive in forward direction), V : volume of the active layer, $r(N)$: nonstimulated recombination rate, $G(N)$: gain function (per unit time), $S(t) \sim P(t)$: average photon density in the active layer. The recombination rate can be modeled by

$$r(N) = \frac{N - n_i}{\tau}, \quad \text{with} \quad n_i = n_t \exp \left(-\frac{U_g}{U_T} \right) \quad (4)$$

being the intrinsic concentration of the active material. The n_i -contribution to r is usually neglected in lasers, because it is extremely small. When operating with reverse voltage, however, N can become even smaller, in which case this contribution gives the saturation value of the reverse dark current

$$I_s = \frac{eVn_i}{\tau}. \quad (5)$$

For the gain function, the logarithmic model

$$G(N) = G'n_t \ln \left(\frac{N}{n_t} \right) \sim U_F(N) - U_g \quad (6)$$

seems to be more reasonable than the linear one, because it provides the very high absorption values at reverse voltages $U_F < 0$.

III. FULL MODEL

Applying Kirchoff's fundamental node and mesh laws to the given quasistationary[1] electrical circuit, all the given model components can be combined. When using those quantities as dynamical variables whose derivatives appear in Eqs. (1) and (3), one arrives at

$$\dot{N} = \frac{I}{eV} - r(N) - G(N)S(t), \quad I = \frac{U_C - U_F(N)}{R} \quad (7)$$

$$\dot{U}_C = \frac{I_L - I}{C}, \quad (8)$$

$$\dot{I}_L = \frac{U_0 - U_C}{L}. \quad (9)$$

In my opinion, this is the appropriate model for a short semiconductor saturable absorber. Before a further general discussion or application, I need typical values for the parameters C, L . I know only $R \approx 2\Omega\text{mm/length}$.

[1] radiation losses neglected